



G. Device & Process Modeling, Simulation and Reliability 분과

2019년 2월 15일(금), 09:00-10:45

Room B (마루홀, 2층)

[FB1-G] Advanced Devices II : Nano Devices

좌장: 최성진 교수(국민대학교), 김성호 교수(세종대학교)

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| FB1-G-1 09:00-09:15 | Observation of Mobility and Velocity Behaviors in Ultra Scaled $L_g=15$ nm Silicon Nanowire pMOSFETs with Different Channel Diameters Seunghwan Lee, Jun-Sik Yoon, Jinsu Jeong, and Rock-Hyun Baek <i>Department of Electrical Engineering, POSTECH</i> |
| FB1-G-2 09:15-09:30 | Interplay Between Line Edge Roughness and Interface Traps in Nanoplate VFETs Yeaji Yoo ^{1,2} , Kyul Ko ^{1,2} , Myounggon Kang ³ , Jongwook Jeon ⁴ , and Hyungcheol Shin ^{1,2} ¹ <i>Inter-University Semiconductor Research Center, Seoul National University,</i> ² <i>School of Electrical Engineering and Computer Science, Seoul National University,</i> ³ <i>Department of Electronics Engineering, Korea National University of Transportation,</i> ⁴ <i>Department</i> |
| FB1-G-3 09:30-09:45 | The Parametric Study of Armchair Graphene Nanoribbon FET by NEGF Method Ji-Hyun Hur <i>Department of Electrical Engineering, Sejong University</i> |
| FB1-G-4 09:45-10:00 | Si-Based Promising Two Dimensional Device : Si/GaP nFET Bokyeom Kim and Mincheol Shin <i>School of Electrical Engineering, KAIST</i> |
| FB1-G-5 10:00-10:15 | Optimization of Vertical Nanowire Transistors for 3.5 nm Technology Node Jaeyeol Park ^{1,2} , Changbeom Woo ^{1,2} , Shinkeun Kim ^{1,2} , Dongjun Lee ^{1,2} , Myounggon Kang ³ , Jongwook Jeon ⁴ , and Hyungcheol Shin ^{1,2} ¹ <i>Inter-University Semiconductor Research Center, Seoul National University,</i> ² <i>School of Electrical Engineering and Computer Science, Seoul National University,</i> ³ <i>Department of Electronics Engineering, Korea National University of Transportation,</i> ⁴ <i>Department of Electronics Engineering, Konkuk University</i> |
| FB1-G-6 10:15-10:30 | GaSb/InAs Heterojunction-Based UTB Tunnel FETs: A First-principles Study Yucheo Cho, Yunhee Chang, and Mincheol Shin <i>School of Electronic Engineering, KAIST</i> |
| FB1-G-7 10:30-10:45 | Effect of Low Temperature on the Electron Mobility Enhancement of Strained-Si Nanowire Transistors Geon-Tae Jang and Sung-Min Hong <i>School of Electrical Engineering and Computer Science, GIST</i> |